

Publication

**EP 0791887 A3 19970903**

Application

**EP 97102675 A 19970219**

Priority

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Abstract (en)

[origin: EP0791887A2] A layout input apparatus of the present invention includes: an input section for inputting first coordinate information representing a position of a first circuit portion included in a first semiconductor integrated circuit and second coordinate information representing a position of a second circuit portion included in a second semiconductor integrated circuit. The layout input apparatus further includes a control section for performing a predetermined coordinate transformation with respect to the second coordinate information; and a storage section for storing the first coordinate information as at least a part of first layout data representing a layout of the first semiconductor integrated circuit and storing the transformed second coordinate information as at least a part of second layout data representing a layout of the second semiconductor integrated circuit. <IMAGE>

IPC 1-7

**G06F 17/50**; **H01L 21/60**

IPC 8 full level

**G06F 17/50** (2006.01); **H01L 25/065** (2006.01)

CPC (source: EP KR US)

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Citation (search report)

- [X] EP 0417345 A1 19910320 - IBM [US]
- [X] DATABASE INSPEC INSTITUTE OF ELECTRICAL ENGINEERS, STEVENAGE, GB; CHAN: "Design automation for multichip module-issues and status", XP002033521 & INTERNATIONAL JOURNAL OF HIGH SPEED ELECTRONICS, vol. 2, no. 4, December 1991 (1991-12-01), SINGAPORE, pages 263 - 285
- [X] DATABASE INSPEC INSTITUTE OF ELECTRICAL ENGINEERS, STEVENAGE, GB; SANDBORN ET AL: "Multichip systems and trade-off analysis tool", XP002033522 & JOURNAL OF ELECTRONIC TESTING: THEORY AND APPLICATIONS, vol. 5, no. 2-3, May 1995 (1995-05-01) - August 1994 (1994-08-01), NETHERLANDS, pages 207 - 218

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